

REMARKS

The above amendment introduces no new subject matter. Entry of the foregoing Preliminary Amendment is in order and requested. If there are any questions regarding the proposed amendment to the application, we invite the Examiner to call Applicants' attorney at the telephone number below.

Respectfully submitted,

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“VERSION WITH MARKINGS TO SHOW CHANGES MADE”

In the Specification:

Please amend the paragraph of page 1 lines 4-7 with the following:

The present invention relates to five [two] other applications filed on the same date: A Method and System for Monitoring and Profiling an Integrated Circuit Die Temperature (Atty. Docket: SMQ-087/P6548[/MDF]), An Integrated Temperature Sensor (Atty. Docket: SMQ-088/P6549[/MDF]), Quantifying a Difference Between Nodal Voltages (Atty. Docket: 03226.116001/P6348), Low Voltage Temperature Independent and Temperature Dependent Voltage Generator (Atty. Docket: 03226.112001/P6322) and Temperature Calibration Using On-Chip Electrical Fuses (Atty. Docket: 03226.108001/P6216).

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